
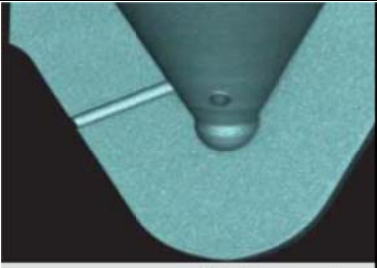
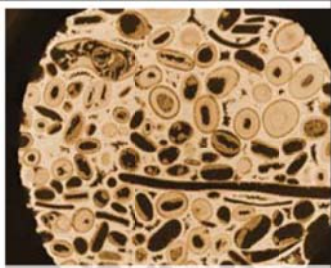


Characterisation

X-ray Tomography Nanotom

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Material class:	Silicon X	Polymer X	Metal X	Ceramic X	Glass X	Organic X	Other X
Short technology description:	<p>The Nanotom is a computerized XRay tomograph. It allows inspecting the parts internally and searching hidden defects and characterizing them. The Nanotom can also rebuilt a CAD file based on the Actual part measured and compare numerically the theoretical one. Tomography is of course a fully Non Destructive Technique, also particularly adapted to Statistical control of parts in industrial environment and also a useful tool for technological developments. Test time is about 2 hours.</p>						
Typical structures and designs:	 <p><i>Injection nozzle</i></p>		 <p><i>Carbonate with oil-filled porosity</i></p>				
Special features:	– No limit						
Limitations, constraints:	– Resolution about 300 nm						
Material examples:	– Alumina, titanium						